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Integrated circuits - EMC evaluation of transceivers -
Part 2: LIN transceivers

EESTI STANDARDI EESSÕNA

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English Version

Integrated circuits - EMC evaluation of transceivers -
Part 2: LIN transceivers
(IEC 62228-2:2016)

Circuits intégrés - Évaluation de la CEM des émetteurs-
récepteurs - Partie 2: Émetteurs-récepteurs LIN
(IEC 62228-2:2016)

Integrierte Schaltungen - Bewertung der
elektromagnetischen Verträglichkeit von Sende-
Empfangsgeräten - Teil 2: LIN-Sende-Empfangsgeräte
(IEC 62228-2:2016)

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European Committee for Electrotechnical Standardization
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European foreword

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INTEGRATED CIRCUITS – EMC EVALUATION OF TRANSCEIVERS –

Part 2: LIN transceivers

1 Scope

This part of IEC 62228 specifies test and measurement methods for EMC evaluation of LIN transceiver ICs under network condition. It defines test configurations, test conditions, test signals, failure criteria, test procedures, test setups and test boards. It is applicable for standard LIN transceiver ICs and ICs with embedded LIN transceiver and covers

- the emission of RF disturbances,
- the immunity against RF disturbances,
- the immunity against impulses and
- the immunity against electrostatic discharges (ESD).

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61967-1, *Integrated circuits – Measurement of electromagnetic emissions 150 kHz to 1 GHz – Part 1: General conditions and definitions*

IEC 61967-4, *Integrated circuits – Measurement of electromagnetic emissions 150 kHz to 1 GHz – Part 4: Measurement of conducted emissions – 1 Ω /150 Ω direct coupling method*

IEC 62132-1, *Integrated circuits – Measurement of electromagnetic immunity – Part 1: General conditions and definitions*

IEC 62132-4, *Integrated circuits – Measurement of electromagnetic immunity 150 kHz to 1 GHz – Part 4: Direct RF power injection method*

IEC 62215-3, *Integrated circuits – Measurement of impulse immunity – Part 3: Non-synchronous transient injection method*

ISO 7637-2, *Road vehicles — Electrical disturbances from conduction and coupling – Part 2: Electrical transient conduction along supply lines only*

ISO 10605, *Road vehicles – Test methods for electrical disturbances from electrostatic discharge*

ISO 17987-6.2¹, *Road vehicles – Local interconnect network (LIN) – Part 6: Protocol conformance test specification*

¹ To be published.